Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	113
Number of Gates	48000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx32-tq144

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Chip Architecture

The SX family chip architecture provides a unique approach to module organization and chip routing that delivers the best register/logic mix for a wide variety of new and emerging applications.

Module Organization

Actel has arranged all C-cell and R-cell logic modules into horizontal banks called *clusters*. There are two types of *clusters*: Type 1 contains two C-cells and one R-cell, while Type 2 contains one C-cell and two R-cells.

To increase design efficiency and device performance, Actel has further organized these modules into *SuperClusters* (Figure 1-4). SuperCluster 1 is a two-wide grouping of Type 1 clusters. SuperCluster 2 is a two-wide group containing one Type 1 cluster and one Type 2 cluster. SX devices feature more SuperCluster 1 modules than SuperCluster 2 modules because designers typically require significantly more combinatorial logic than flip-flops.

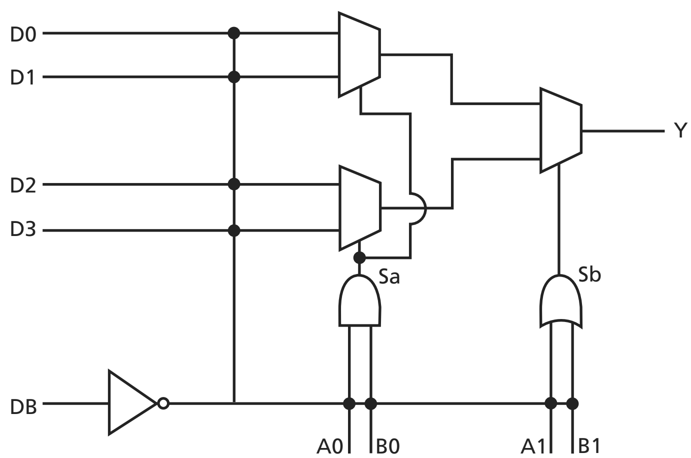


Figure 1-3 • **C-Cell**

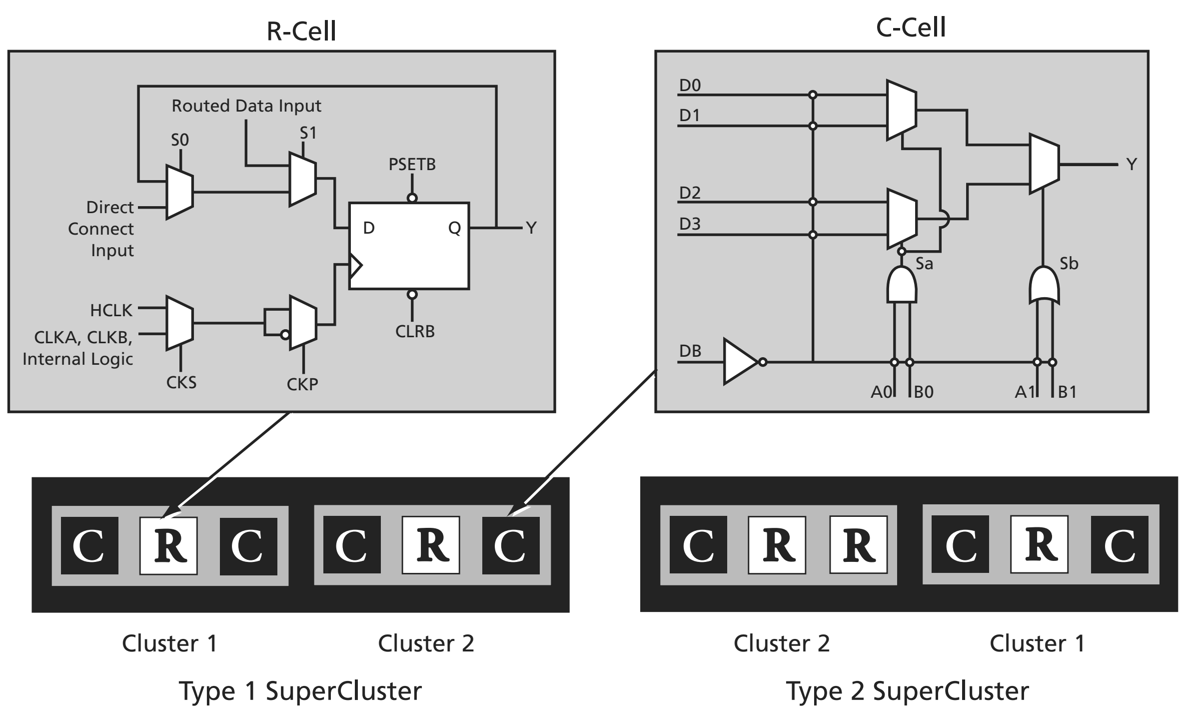


Figure 1-4 • **Cluster Organization**

Boundary Scan Testing (BST)

All SX devices are IEEE 1149.1 compliant. SX devices offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. These functions are controlled through the special test pins in conjunction with the program fuse. The functionality of each pin is described in Table 1-2. In the dedicated test mode, TCK, TDI, and TDO are dedicated pins and cannot be used as regular I/Os. In flexible mode, TMS should be set HIGH through a pull-up resistor of 10 kΩ. TMS can be pulled LOW to initiate the test sequence.

The program fuse determines whether the device is in dedicated or flexible mode. The default (fuse not blown) is flexible mode.

Table 1-2 • **Boundary Scan Pin Functionality**

Program Fuse Blown (Dedicated Test Mode)	Program Fuse Not Blown (Flexible Mode)
TCK, TDI, TDO are dedicated BST pins.	TCK, TDI, TDO are flexible and may be used as I/Os.
No need for pull-up resistor for TMS	Use a pull-up resistor of 10 kΩ on TMS.

Dedicated Test Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, users need to reserve the JTAG pins in Actel's Designer software by checking the "Reserve JTAG" box in "Device Selection Wizard" (Figure 1-7). JTAG pins comply with LVTTL/TTL I/O specification regardless of whether they are used as a user I/O or a JTAG I/O. Refer to the Table 1-5 on page 1-8 for detailed specifications.

Figure 1-7 • **Device Selection Wizard**

Development Tool Support

The SX family of FPGAs is fully supported by both the Actel Libero® Integrated Design Environment (IDE) and Designer FPGA Development software. Actel Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Synplify® for Actel from Synplicity®, ViewDraw® for Actel from Mentor Graphics®, Model*Sim*® HDL Simulator from Mentor Graphics, WaveFormer Lite™ from SynaptiCAD™, and Designer software from Actel. Refer to the Libero IDE flow diagram (located on the Actel website) for more information.

Actel Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can select and lock package pins while only minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators, and the simulation results can be cross-probed with Silicon Explorer II, Actel integrated verification and logic analysis tool. Another tool included in the Designer software is the SmartGen core generator, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design. Actel Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys®, and Cadence® Design Systems. The Designer software is available for both the Windows® and UNIX® operating systems.

Probe Circuit Control Pins

The Silicon Explorer II tool uses the boundary scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the PRA/PRB pins for observation. Figure 1-8 on page 1-7 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

The TDI, TCK, TDO, PRA, and PRB pins should not be used as input or bidirectional ports. Because these pins are active during probing, critical signals input through these pins are not available while probing. In addition, the Security Fuse should not be programmed because doing so disables the Probe Circuitry.

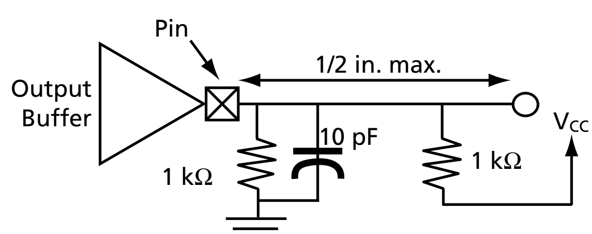
A54SX16P AC Specifications for (PCI Operation)

Table 1-7 • **A54SX16P AC Specifications for (PCI Operation)**

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 1.4$[1]	–44		mA
		$1.4 \leq V_{OUT} < 2.4$[1, 2]	$-44 + (V_{OUT} - 1.4)/0.024$		mA
		$3.1 < V_{OUT} < V_{CC}$[1, 3]		EQ 1-1 on page 1-11	
	(Test Point)	$V_{OUT} = 3.1$[3]		–142	mA
$I_{OL(AC)}$	Switching Current High	$V_{OUT} \geq 2.2$[1]	95		mA
		$2.2 > V_{OUT} > 0.55$[1]	$V_{OUT}/0.023$		
		$0.71 > V_{OUT} > 0$[1, 3]		EQ 1-2 on page 1-11	mA
	(Test Point)	$V_{OUT} = 0.71$[3]		206	mA
I_{CL}	Low Clamp Current	$-5 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$		mA
$slew_R$	Output Rise Slew Rate	0.4 V to 2.4 V load[4]	1	5	V/ns
$slew_F$	Output Fall Slew Rate	2.4 V to 0.4 V load[4]	1	5	V/ns

Notes:

1. *Refer to the V/I curves in Figure 1-9 on page 1-11. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half-size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.*
2. *Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.*
3. *Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (A and B) are provided with the respective diagrams in Figure 1-9 on page 1-11. The equation defined maxima should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.*
4. *This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur, and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.*



A54SX16P DC Specifications (3.3 V PCI Operation)

Table 1-8 • **A54SX16P DC Specifications (3.3 V PCI Operation)**

Symbol	Parameter	Condition	Min.	Max.	Units
V_{CCA}	Supply Voltage for Array		3.0	3.6	V
V_{CCR}	Supply Voltage required for Internal Biasing		3.0	3.6	V
V_{CCI}	Supply Voltage for I/Os		3.0	3.6	V
V_{IH}	Input High Voltage		$0.5V_{CC}$	$V_{CC} + 0.5$	V
V_{IL}	Input Low Voltage		–0.5	$0.3V_{CC}$	V
I_{IPU}	Input Pull-up Voltage[1]		$0.7V_{CC}$		V
I_{IL}	Input Leakage Current[2]	$0 < V_{IN} < V_{CC}$		±10	µA
V_{OH}	Output High Voltage	I_{OUT} = –500 µA	$0.9V_{CC}$		V
V_{OL}	Output Low Voltage	I_{OUT} = 1500 µA		$0.1V_{CC}$	V
C_{IN}	Input Pin Capacitance[3]			10	pF
C_{CLK}	CLK Pin Capacitance		5	12	pF
C_{IDSEL}	IDSEL Pin Capacitance[4]			8	pF

Notes:

1. *This specification should be guaranteed by design. It is the minimum voltage to which pull-up resistors are calculated to pull a floated network. Applications sensitive to static power utilization should assure that the input buffer is conducting minimum current at this input voltage.*
2. *Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.*
3. *Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).*
4. *Lower capacitance on this input-only pin allows for non-resistive coupling to AD[xx].*

Evaluating Power in SX Devices

A critical element of system reliability is the ability of electronic devices to safely dissipate the heat generated during operation. The thermal characteristics of a circuit depend on the device and package used, the operating temperature, the operating current, and the system's ability to dissipate heat.

You should complete a power evaluation early in the design process to help identify potential heat-related problems in the system and to prevent the system from exceeding the device’s maximum allowed junction temperature.

The actual power dissipated by most applications is significantly lower than the power the package can dissipate. However, a thermal analysis should be performed for all projects. To perform a power evaluation, follow these steps:

1. Estimate the power consumption of the application.
2. Calculate the maximum power allowed for the device and package.
3. Compare the estimated power and maximum power values.

Estimating Power Consumption

The total power dissipation for the SX family is the sum of the DC power dissipation and the AC power dissipation. Use EQ 1-5 to calculate the estimated power consumption of your application.

$$P_{Total} = P_{DC} + P_{AC}$$

EQ 1-5

DC Power Dissipation

The power due to standby current is typically a small component of the overall power. The Standby power is shown in Table 1-12 for commercial, worst-case conditions (70°C).

Table 1-12 • **Standby Power**

I_{CC}	V_{CC}	Power
4 mA	3.6 V	14.4 mW

The DC power dissipation is defined in EQ 1-6.

$$P_{DC} = (I_{standby}) \times V_{CCA} + (I_{standby}) \times V_{CCR} + (I_{standby}) \times V_{CCI} + xV_{OL} \times I_{OL} + y(V_{CCI} - V_{OH}) \times V_{OH}$$

EQ 1-6

AC Power Dissipation

The power dissipation of the SX Family is usually dominated by the dynamic power dissipation. Dynamic power dissipation is a function of frequency, equivalent capacitance, and power supply voltage. The AC power dissipation is defined in EQ 1-7 and EQ 1-8.

$$P_{AC} = P_{Module} + P_{RCLKA\ Net} + P_{RCLKB\ Net} + P_{HCLK\ Net} + P_{Output\ Buffer} + P_{Input\ Buffer}$$

EQ 1-7

$$P_{AC} = V_{CCA}^2 \times [(m \times C_{EQM} \times f_m)_{Module} + (n \times C_{EQI} \times f_n)_{Input\ Buffer} + (p \times (C_{EQO} + C_L) \times f_p)_{Output\ Buffer} + (0.5 \times (q_1 \times C_{EQCR} \times f_{q1}) + (r_1 \times f_{q1}))_{RCLKA} + (0.5 \times (q2 \times CEQCR \times f_{q2}) + (r2 \times f_{q2}))RCLKB + (0.5 \times (s_1 \times C_{EQHV} \times f_{s1}) + (C_{EQHF} \times f_{s1}))_{HCLK}]$$

EQ 1-8

Definition of Terms Used in Formula

m	=	Number of logic modules switching at f_m
n	=	Number of input buffers switching at f_n
p	=	Number of output buffers switching at f_p
q_1	=	Number of clock loads on the first routed array clock
q_2	=	Number of clock loads on the second routed array clock
x	=	Number of I/Os at logic low
y	=	Number of I/Os at logic high
r_1	=	Fixed capacitance due to first routed array clock
r_2	=	Fixed capacitance due to second routed array clock
s_1	=	Number of clock loads on the dedicated array clock
C_{EQM}	=	Equivalent capacitance of logic modules in pF
C_{EQI}	=	Equivalent capacitance of input buffers in pF
C_{EQO}	=	Equivalent capacitance of output buffers in pF
C_{EQCR}	=	Equivalent capacitance of routed array clock in pF
C_{EQHV}	=	Variable capacitance of dedicated array clock
C_{EQHF}	=	Fixed capacitance of dedicated array clock
C_L	=	Output lead capacitance in pF
f_m	=	Average logic module switching rate in MHz
f_n	=	Average input buffer switching rate in MHz
f_p	=	Average output buffer switching rate in MHz
f_{q1}	=	Average first routed array clock rate in MHz
f_{q2}	=	Average second routed array clock rate in MHz
f_{s1}	=	Average dedicated array clock rate in MHz

Table 1-15 • **Package Thermal Characteristics**

Package Type	Pin Count	θ_{jc}	θ_{ja} Still Air	θ_{ja} 300 ft/min.	Units
Plastic Leaded Chip Carrier (PLCC)	84	12	32	22	°C/W
Thin Quad Flat Pack (TQFP)	144	11	32	24	°C/W
Thin Quad Flat Pack (TQFP)	176	11	28	21	°C/W
Very Thin Quad Flatpack (VQFP)	100	10	38	32	°C/W
Plastic Quad Flat Pack (PQFP) without Heat Spreader	208	8	30	23	°C/W
Plastic Quad Flat Pack (PQFP) with Heat Spreader	208	3.8	20	17	°C/W
Plastic Ball Grid Array (PBGA)	272	3	20	14.5	°C/W
Plastic Ball Grid Array (PBGA)	313	3	23	17	°C/W
Plastic Ball Grid Array (PBGA)	329	3	18	13.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	144	3.8	38.8	26.7	°C/W

Note: *SX08 does not have a heat spreader.*

Table 1-16 • **Temperature and Voltage Derating Factors***

V_{CCA}	Junction Temperature						
	–55	**–40**	**0**	**25**	**70**	**85**	**125**
3.0	0.75	0.78	0.87	0.89	1.00	1.04	1.16
3.3	0.70	0.73	0.82	0.83	0.93	0.97	1.08
3.6	0.66	0.69	0.77	0.78	0.87	0.92	1.02

Note: **Normalized to worst-case commercial, T_J = 70°C, V_{CCA} = 3.0 V*

A54SX08 Timing Characteristics

Table 1-17 • **A54SX08 Timing Characteristics**
(Worst-Case Commercial Conditions, V_{CCR} = 4.75 V, V_{CCA}, V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	'–3' Speed Min.	'–3' Speed Max.	'–2' Speed Min.	'–2' Speed Max.	'–1' Speed Min.	'–1' Speed Max.	'Std' Speed Min.	'Std' Speed Max.	Units
C-Cell Propagation Delays[1]										
t_{PD}	Internal Array Module		0.6		0.7		0.8		0.9	ns
Predicted Routing Delays[2]										
t_{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1	ns
t_{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.4		0.4		0.5	ns
t_{RD1}	FO = 1 Routing Delay		0.3		0.4		0.4		0.5	ns
t_{RD2}	FO = 2 Routing Delay		0.6		0.7		0.8		0.9	ns
t_{RD3}	FO = 3 Routing Delay		0.8		0.9		1.0		1.2	ns
t_{RD4}	FO = 4 Routing Delay		1.0		1.2		1.4		1.6	ns
t_{RD8}	FO = 8 Routing Delay		1.9		2.2		2.5		2.9	ns
t_{RD12}	FO = 12 Routing Delay		2.8		3.2		3.7		4.3	ns
R-Cell Timing										
t_{RCO}	Sequential Clock-to-Q		0.8		1.1		1.2		1.4	ns
t_{CLR}	Asynchronous Clear-to-Q		0.5		0.6		0.7		0.8	ns
t_{PRESET}	Asynchronous Preset-to-Q		0.7		0.8		0.9		1.0	ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.5		0.5		0.7		0.8		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.4		1.6		1.8		2.1		ns
Input Module Propagation Delays										
t_{INYH}	Input Data Pad-to-Y HIGH		1.5		1.7		1.9		2.2	ns
t_{INYL}	Input Data Pad-to-Y LOW		1.5		1.7		1.9		2.2	ns
Input Module Predicted Routing Delays[2]										
t_{IRD1}	FO = 1 Routing Delay		0.3		0.4		0.4		0.5	ns
t_{IRD2}	FO = 2 Routing Delay		0.6		0.7		0.8		0.9	ns
t_{IRD3}	FO = 3 Routing Delay		0.8		0.9		1.0		1.2	ns
t_{IRD4}	FO = 4 Routing Delay		1.0		1.2		1.4		1.6	ns
t_{IRD8}	FO = 8 Routing Delay		1.9		2.2		2.5		2.9	ns
t_{IRD12}	FO = 12 Routing Delay		2.8		3.2		3.7		4.3	ns

Note:

1. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

A54SX16P Timing Characteristics

Table 1-19 • **A54SX16P Timing Characteristics**
(Worst-Case Commercial Conditions, V_{CCR} = 4.75 V, V_{CCA},V_{CCI} = 3.0 V, T_J = 70°C)

		'–3' Speed		'–2' Speed		'–1' Speed		'Std' Speed		
Parameter	**Description**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
C-Cell Propagation Delays[1]										
t_{PD}	Internal Array Module		0.6		0.7		0.8		0.9	ns
Predicted Routing Delays[2]										
t_{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1	ns
t_{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.4		0.4		0.5	ns
t_{RD1}	FO = 1 Routing Delay		0.3		0.4		0.4		0.5	ns
t_{RD2}	FO = 2 Routing Delay		0.6		0.7		0.8		0.9	ns
t_{RD3}	FO = 3 Routing Delay		0.8		0.9		1.0		1.2	ns
t_{RD4}	FO = 4 Routing Delay		1.0		1.2		1.4		1.6	ns
t_{RD8}	FO = 8 Routing Delay		1.9		2.2		2.5		2.9	ns
t_{RD12}	FO = 12 Routing Delay		2.8		3.2		3.7		4.3	ns
R-Cell Timing										
t_{RCO}	Sequential Clock-to-Q		0.9		1.1		1.3		1.4	ns
t_{CLR}	Asynchronous Clear-to-Q		0.5		0.6		0.7		0.8	ns
t_{PRESET}	Asynchronous Preset-to-Q		0.7		0.8		0.9		1.0	ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.5		0.5		0.7		0.8		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.4		1.6		1.8		2.1		ns
Input Module Propagation Delays										
t_{INYH}	Input Data Pad-to-Y HIGH		1.5		1.7		1.9		2.2	ns
t_{INYL}	Input Data Pad-to-Y LOW		1.5		1.7		1.9		2.2	ns
Predicted Input Routing Delays[2]										
t_{IRD1}	FO = 1 Routing Delay		0.3		0.4		0.4		0.5	ns
t_{IRD2}	FO = 2 Routing Delay		0.6		0.7		0.8		0.9	ns
t_{IRD3}	FO = 3 Routing Delay		0.8		0.9		1.0		1.2	ns
t_{IRD4}	FO = 4 Routing Delay		1.0		1.2		1.4		1.6	ns
t_{IRD8}	FO = 8 Routing Delay		1.9		2.2		2.5		2.9	ns
t_{IRD12}	FO = 12 Routing Delay		2.8		3.2		3.7		4.3	ns

Note:

1. *For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn}, t_{RCO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*
3. *Delays based on 10 pF loading.*

Table 1-19 • **A54SX16P Timing Characteristics (Continued)**
(Worst-Case Commercial Conditions, V_{CCR} = 4.75 V, V_{CCA},V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	'–3' Speed Min.	'–3' Speed Max.	'–2' Speed Min.	'–2' Speed Max.	'–1' Speed Min.	'–1' Speed Max.	'Std' Speed Min.	'Std' Speed Max.	Units
TTL/PCI Output Module Timing										
t_{DLH}	Data-to-Pad LOW to HIGH		1.5		1.7		2.0		2.3	ns
t_{DHL}	Data-to-Pad HIGH to LOW		1.9		2.2		2.4		2.9	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.3		2.6		3.0		3.5	ns
t_{ENZH}	Enable-to-Pad, Z to H		1.5		1.7		1.9		2.3	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.7		3.1		3.5		4.1	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.9		3.3		3.7		4.4	ns
PCI Output Module Timing[3]										
t_{DLH}	Data-to-Pad LOW to HIGH		1.8		2.0		2.3		2.7	ns
t_{DHL}	Data-to-Pad HIGH to LOW		1.7		2.0		2.2		2.6	ns
t_{ENZL}	Enable-to-Pad, Z to L		0.8		1.0		1.1		1.3	ns
t_{ENZH}	Enable-to-Pad, Z to H		1.2		1.2		1.5		1.8	ns
t_{ENLZ}	Enable-to-Pad, L to Z		1.0		1.1		1.3		1.5	ns
t_{ENHZ}	Enable-to-Pad, H to Z		1.1		1.3		1.5		1.7	ns
TTL Output Module Timing										
t_{DLH}	Data-to-Pad LOW to HIGH		2.1		2.5		2.8		3.3	ns
t_{DHL}	Data-to-Pad HIGH to LOW		2.0		2.3		2.6		3.1	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.5		2.9		3.2		3.8	ns
t_{ENZH}	Enable-to-Pad, Z to H		3.0		3.5		3.9		4.6	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.3		2.7		3.1		3.6	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.9		3.3		3.7		4.4	ns

Note:

1. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*
3. *Delays based on 10 pF loading.*

Pin Description

CLKA/B **Clock A and B**

These pins are 3.3 V / 5.0 V PCI/TTL clock inputs for clock distribution networks. The clock input is buffered prior to clocking the R-cells. If not used, this pin must be set LOW or HIGH on the board. It must not be left floating. (For A54SX72A, these clocks can be configured as bidirectional.)

GND **Ground**

LOW supply voltage.

HCLK **Dedicated (hardwired) Array Clock**

This pin is the 3.3 V / 5.0 V PCI/TTL clock input for sequential modules. This input is directly wired to each R-cell and offers clock speeds independent of the number of R-cells being driven. If not used, this pin must be set LOW or HIGH on the board. It must not be left floating.

I/O **Input/Output**

The I/O pin functions as an input, output, tristate, or bidirectional buffer. Based on certain configurations, input and output levels are compatible with standard TTL, LVTTL, 3.3 V PCI or 5.0 V PCI specifications. Unused I/O pins are automatically tristated by the Designer Series software.

NC **No Connection**

This pin is not connected to circuitry within the device.

PRA, I/O **Probe A**

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.

PRB, I/O **Probe B**

The Probe B pin is used to output data from any node within the device. This diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.

TCK **Test Clock**

Test clock input for diagnostic probe and device programming. In flexible mode, TCK becomes active when the TMS pin is set LOW (refer to Table 1-2 on page 1-6). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDI **Test Data Input**

Serial input for boundary scan testing and diagnostic probe. In flexible mode, TDI is active when the TMS pin is set LOW (refer to Table 1-2 on page 1-6). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDO **Test Data Output**

Serial output for boundary scan testing. In flexible mode, TDO is active when the TMS pin is set LOW (refer to Table 1-2 on page 1-6). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TMS **Test Mode Select**

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI, and TDO pins are boundary scan pins (refer to Table 1-2 on page 1-6). Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications.

V_{CCI} **Supply Voltage**

Supply voltage for I/Os. See Table 1-1 on page 1-5.

V_{CCA} **Supply Voltage**

Supply voltage for Array. See Table 1-1 on page 1-5.

V_{CCR} **Supply Voltage**

Supply voltage for input tolerance (required for internal biasing). See Table 1-1 on page 1-5.

Package Pin Assignments

84-Pin PLCC

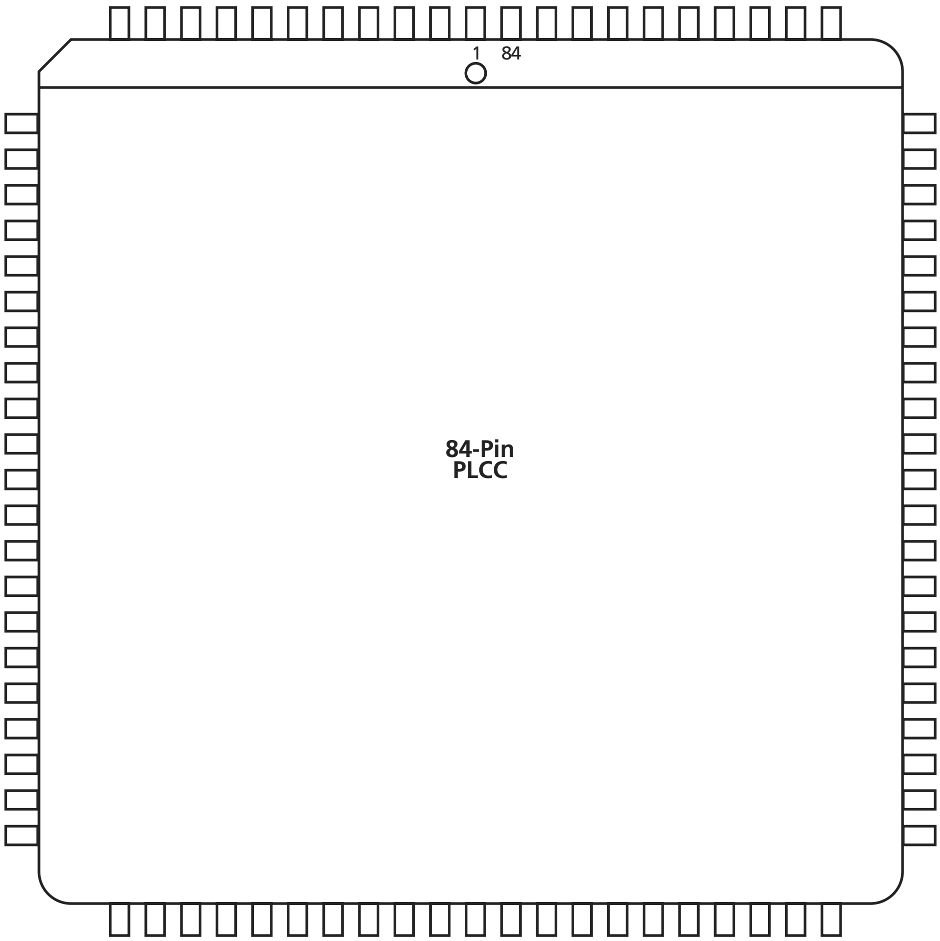


Figure 2-1 • **84-Pin PLCC (Top View)**

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at http://www.actel.com/products/rescenter/package/index.html.

176-Pin TQFP

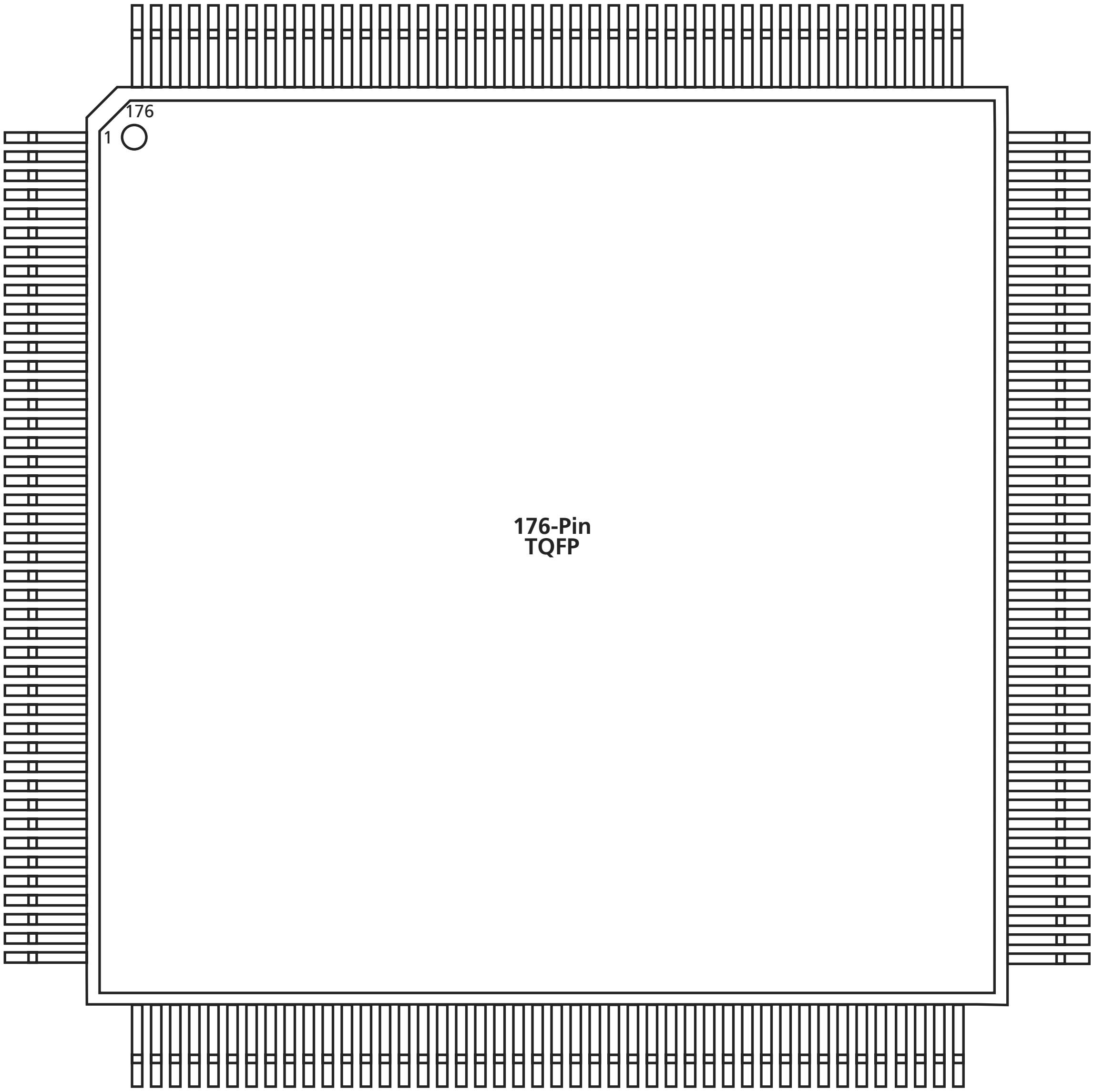


Figure 2-4 • **176-Pin TQFP (Top View)**

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at http://www.actel.com/products/rescenter/package/index.html.

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	NC	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	I/O	I/O	I/O
10	TMS	TMS	TMS
11	V_{CCI}	V_{CCI}	V_{CCI}
12	NC	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	I/O	I/O	I/O
21	GND	GND	GND
22	V_{CCA}	V_{CCA}	V_{CCA}
23	GND	GND	GND
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	I/O	I/O	I/O
29	I/O	I/O	I/O
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	V_{CCI}	V_{CCI}	V_{CCI}
33	V_{CCA}	V_{CCA}	V_{CCA}
34	I/O	I/O	I/O

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
35	I/O	I/O	I/O
36	I/O	I/O	I/O
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	NC	I/O	I/O
41	I/O	I/O	I/O
42	NC	I/O	I/O
43	I/O	I/O	I/O
44	GND	GND	GND
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	V_{CCI}	V_{CCI}	V_{CCI}
53	I/O	I/O	I/O
54	NC	I/O	I/O
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	NC	I/O	I/O
58	I/O	I/O	I/O
59	I/O	I/O	I/O
60	I/O	I/O	I/O
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	PRB, I/O	PRB, I/O	PRB, I/O
65	GND	GND	GND
66	V_{CCA}	V_{CCA}	V_{CCA}
67	V_{CCR}	V_{CCR}	V_{CCR}
68	I/O	I/O	I/O

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
137	I/O	I/O	I/O
138	I/O	I/O	I/O
139	I/O	I/O	I/O
140	V_{CCI}	V_{CCI}	V_{CCI}
141	I/O	I/O	I/O
142	I/O	I/O	I/O
143	I/O	I/O	I/O
144	I/O	I/O	I/O
145	I/O	I/O	I/O
146	I/O	I/O	I/O
147	I/O	I/O	I/O
148	I/O	I/O	I/O
149	I/O	I/O	I/O
150	I/O	I/O	I/O
151	I/O	I/O	I/O
152	CLKA	CLKA	CLKA
153	CLKB	CLKB	CLKB
154	V_{CCR}	V_{CCR}	V_{CCR}
155	GND	GND	GND
156	V_{CCA}	V_{CCA}	V_{CCA}

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
157	PRA, I/O	PRA, I/O	PRA, I/O
158	I/O	I/O	I/O
159	I/O	I/O	I/O
160	I/O	I/O	I/O
161	I/O	I/O	I/O
162	I/O	I/O	I/O
163	I/O	I/O	I/O
164	I/O	I/O	I/O
165	I/O	I/O	I/O
166	I/O	I/O	I/O
167	I/O	I/O	I/O
168	NC	I/O	I/O
169	V_{CCI}	V_{CCI}	V_{CCI}
170	I/O	I/O	I/O
171	NC	I/O	I/O
172	NC	I/O	I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	I/O	I/O	I/O
176	TCK, I/O	TCK, I/O	TCK, I/O

100-Pin VQFP

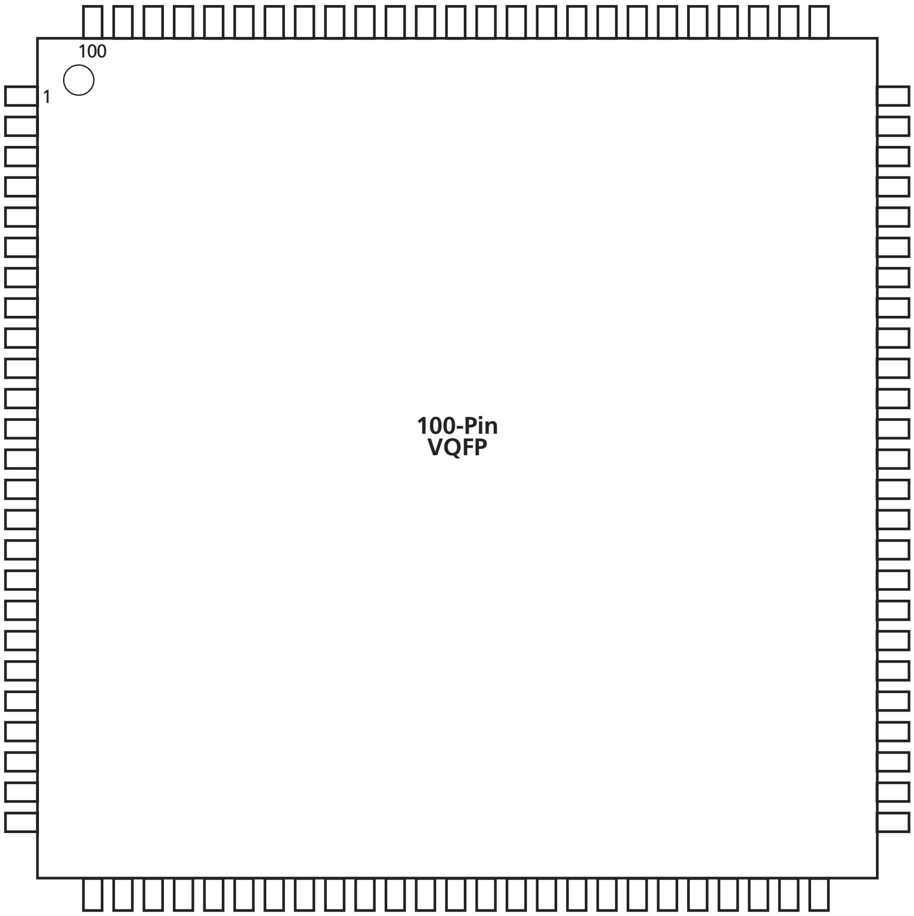


Figure 2-5 • **100-Pin VQFP (Top View)**

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at http://www.actel.com/products/rescenter/package/index.html.

100-Pin VQFP		
Pin Number	**A54SX08 Function**	**A54SX16, A54SX16P Function**
1	GND	GND
2	TDI, I/O	TDI, I/O
3	I/O	I/O
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	TMS	TMS
8	V_{CCI}	V_{CCI}
9	GND	GND
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	I/O	I/O
15	I/O	I/O
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	V_{CCI}	V_{CCI}
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	I/O	I/O
33	I/O	I/O
34	PRB, I/O	PRB, I/O

100-Pin VQFP		
Pin Number	**A54SX08 Function**	**A54SX16, A54SX16P Function**
35	V_{CCA}	V_{CCA}
36	GND	GND
37	V_{CCR}	V_{CCR}
38	I/O	I/O
39	HCLK	HCLK
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	I/O	I/O
44	V_{CCI}	V_{CCI}
45	I/O	I/O
46	I/O	I/O
47	I/O	I/O
48	I/O	I/O
49	TDO, I/O	TDO, I/O
50	I/O	I/O
51	GND	GND
52	I/O	I/O
53	I/O	I/O
54	I/O	I/O
55	I/O	I/O
56	I/O	I/O
57	V_{CCA}	V_{CCA}
58	V_{CCI}	V_{CCI}
59	I/O	I/O
60	I/O	I/O
61	I/O	I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	I/O	I/O
67	V_{CCA}	V_{CCA}
68	GND	GND

100-Pin VQFP		
Pin Number	**A54SX08 Function**	**A54SX16, A54SX16P Function**
69	GND	GND
70	I/O	I/O
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	I/O	I/O
75	I/O	I/O
76	I/O	I/O
77	I/O	I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O
81	I/O	I/O
82	V_{CCI}	V_{CCI}
83	I/O	I/O
84	I/O	I/O
85	I/O	I/O
86	I/O	I/O
87	CLKA	CLKA
88	CLKB	CLKB
89	V_{CCR}	V_{CCR}
90	V_{CCA}	V_{CCA}
91	GND	GND
92	PRA, I/O	PRA, I/O
93	I/O	I/O
94	I/O	I/O
95	I/O	I/O
96	I/O	I/O
97	I/O	I/O
98	I/O	I/O
99	I/O	I/O
100	TCK, I/O	TCK, I/O

329-Pin PBGA

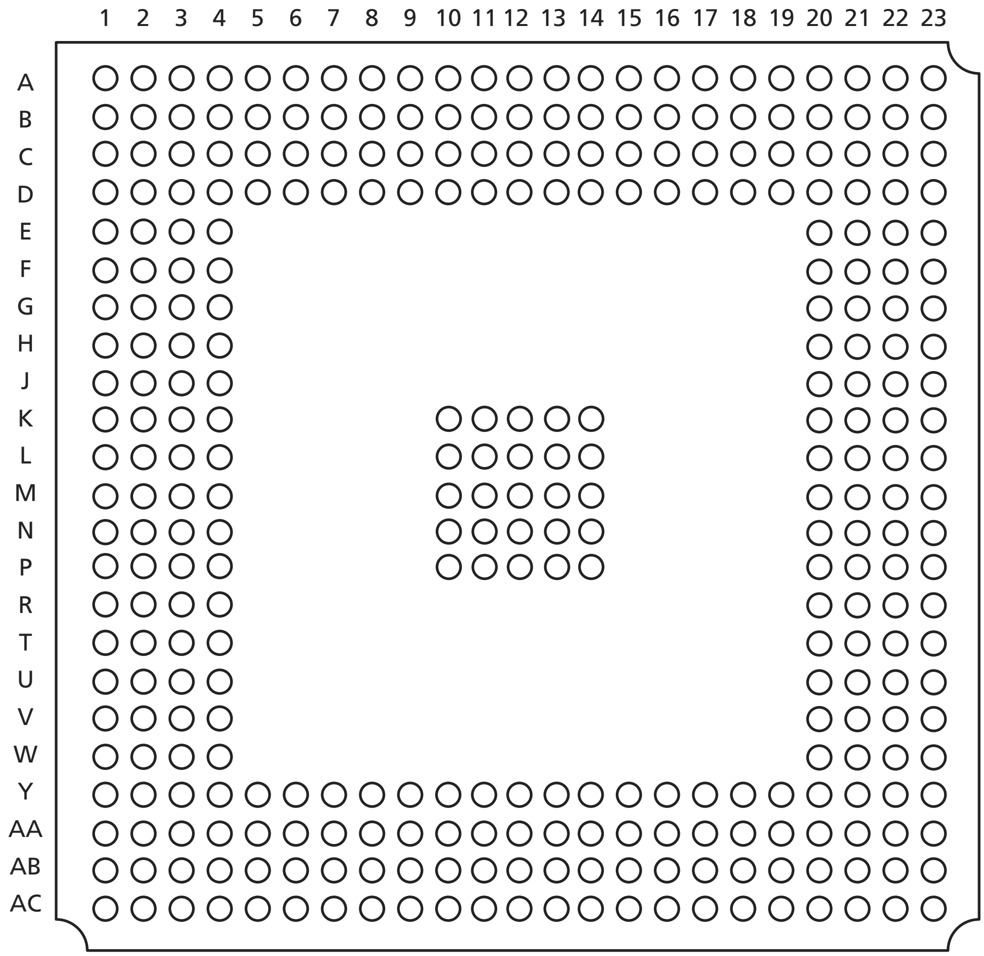


Figure 2-7 • **329-Pin PBGA (Top View)**

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at http://www.actel.com/products/rescenter/package/index.html.

329-Pin PBGA	
Pin Number	**A54SX32 Function**
T22	I/O
T23	I/O
U1	I/O
U2	I/O
U3	V_{CCA}
U4	I/O
U20	I/O
U21	V_{CCA}
U22	I/O
U23	I/O
V1	V_{CCI}
V2	I/O
V3	I/O

329-Pin PBGA	
Pin Number	**A54SX32 Function**
V4	I/O
V20	I/O
V21	I/O
V22	I/O
V23	I/O
W1	I/O
W2	I/O
W3	I/O
W4	I/O
W20	I/O
W21	I/O
W22	I/O

329-Pin PBGA	
Pin Number	**A54SX32 Function**
W23	NC
Y1	NC
Y2	I/O
Y3	I/O
Y4	GND
Y5	I/O
Y6	I/O
Y7	I/O
Y8	I/O
Y9	I/O
Y10	I/O
Y11	I/O

329-Pin PBGA	
Pin Number	**A54SX32 Function**
Y12	V_{CCA}
Y13	V_{CCR}
Y14	I/O
Y15	I/O
Y16	I/O
Y17	I/O
Y18	I/O
Y19	I/O
Y20	GND
Y21	I/O
Y22	I/O
Y23	I/O

Datasheet Information

List of Changes

The following table lists critical changes that were made in the current version of the document.

Previous Version	Changes in Current Version (v3.2)	Page
v3.1 (June 2003)	The "Ordering Information" was updated to include RoHS information.	1-ii
	The Product Plan was removed since all products have been released.	N/A
	Information concerning the TRST pin in the "Probe Circuit Control Pins" section was removed.	1-6
	The "Dedicated Test Mode" section is new.	1-6
	The "Programming" section is new.	1-7
	A note was added to the "Power-Up Sequencing" table.	1-15
	A note was added to the "Power-Down Sequencing" table. The 3.3 V comments were updated for the following devices: A54SX08, A54SX16, A54SX32.	1-15
	U11 and U13 were added to the "313-Pin PBGA" table.	2-17
v3.0.1	Storage temperature in Table 1-3 was updated.	1-7
	Table 1-1 was updated.	1-5

Datasheet Categories

In order to provide the latest information to designers, some datasheets are published before data has been fully characterized. Datasheets are designated as "Product Brief," "Advanced," "Production," and "Datasheet Supplement." The definitions of these categories are as follows:

Product Brief

The product brief is a summarized version of a datasheet (advanced or production) containing general product information. This brief gives an overview of specific device and family information.

Advanced

This datasheet version contains initial estimated information based on simulation, other products, devices, or speed grades. This information can be used as estimates, but not for production.

Unmarked (production)

This datasheet version contains information that is considered to be final.

Datasheet Supplement

The datasheet supplement gives specific device information for a derivative family that differs from the general family datasheet. The supplement is to be used in conjunction with the datasheet to obtain more detailed information and for specifications that do not differ between the two families.

International Traffic in Arms Regulations (ITAR) and Export Administration Regulations (EAR)

The products described in this datasheet are subject to the International Traffic in Arms Regulations (ITAR) or the Export Administration Regulations (EAR). They may require an approved export license prior to their export. An export can include a release or disclosure to a foreign national inside or outside the United States.